

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
40	0.0045 at V _{GS} = 10 V	18	8 nC			
40	0.0065 at V _{GS} = 4.5 V	14.5	0110			

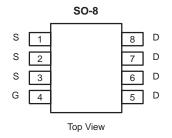
FEATURES

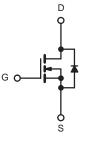
- Halogen-free According to IEC 61249-2-21
- TrenchFET[®] Power MOSFET
- 100 % R_g and UIS Tested

APPLICATIONS

- Notebook CPU Core
 - High-Side Switch







N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	40	V	
Gate-Source Voltage		V _{GS}	± 20	v	
	T _C = 25 °C		18		
Continuous Drain Current ($T_{I} = 150 \ ^{\circ}C$)	T _C = 70 °C		13.5		
Continuous Drain Current (1j = 150°C)	T _A = 25 °C		12 ^{b, c}		
	T _A = 70 °C		9.6 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	50	A	
	T _C = 25 °C	L	4.5		
Continuous Source-Drain Diode Current	T _A = 25 °C	Is I	2.2 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	20		
Avalanche Energy		E _{AS}	20	mJ	
	T _C = 25 °C		5		
Movimum Dower Dissinction	T _C = 70 °C	P _D	3.2	w	
Maximum Power Dissipation	T _A = 25 °C		2.5 ^{b, c}	vv	
	T _A = 70 °C	1 [1.6 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	38	50	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	20	25	0,00

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 85 °C/W.

CEM4042

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static		•					
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$	40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L 050		34		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- Ι _D = 250 μΑ		- 4.7			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.0		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zana Cata Maltana Duain Comunit		$V_{DS} = 40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	30			Α	
	Р	V _{GS} = 10 V, I _D = 10 A	0.0038				
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 7 A		0.0057		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A		30		S	
Dynamic ^b		•					
Input Capacitance	C _{iss}			985		pF	
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		205			
Reverse Transfer Capacitance	C _{rss}	1		76			
Tatal Oata Obarra	Q _g	$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$	18	18	27	nC	
Total Gate Charge	Qg			8	12		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		2.4			
Gate-Drain Charge	Q _{gd}			2.3			
Gate Resistance	Rg	f = 1 MHz	0.3	1.3	2.6	Ω	
Turn-On Delay Time	t _{d(on)}			14	25	- - - ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		12	24		
Turn-Off Delay Time	t _{d(off)}	$I_{D}\cong$ 10 A, V_{GEN} = 4.5 V, R_{g} = 1 Ω		19	35		
Fall Time	t _f			9	18		
Turn-On Delay Time	t _{d(on)}			8	16	113	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		10	20	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		16	30		
Fall Time	t _f			9	18		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			4.5	^	
Pulse Diode Forward Current ^a	I _{SM}				50	A	
Body Diode Voltage	V_{SD}	I _S = 3 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			14	28	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 10 A, dl/dt = 100 A/μs, T _J = 25 °C		5	10	nC	
Reverse Recovery Fall Time	t _a	$F = 10 \text{ A}, \text{ and } = 100 \text{ A/} \mu\text{s}, \text{I} \text{J} = 25 \text{ C}$		8		-	
Reverse Recovery Rise Time	t _b			6		ns	

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %

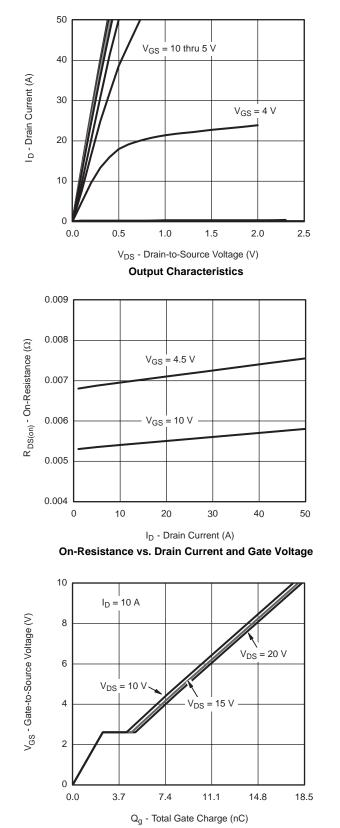
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

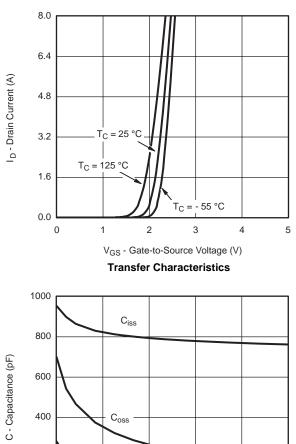
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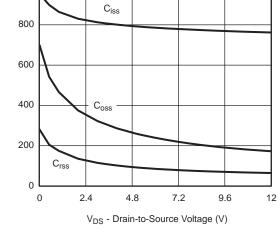


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

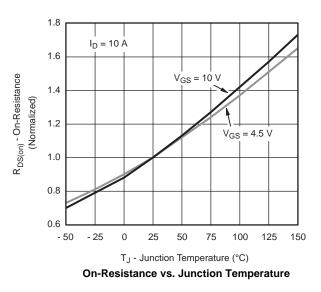


Gate Charge





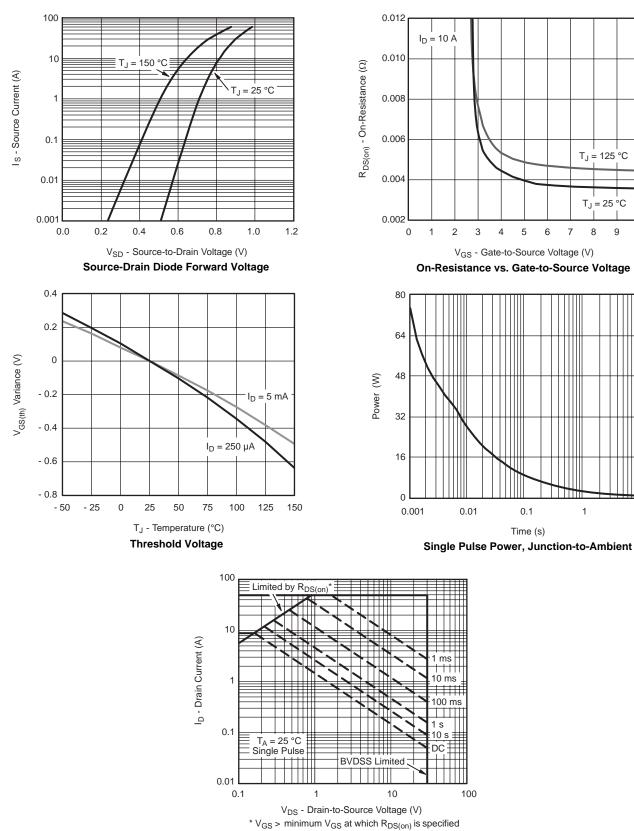






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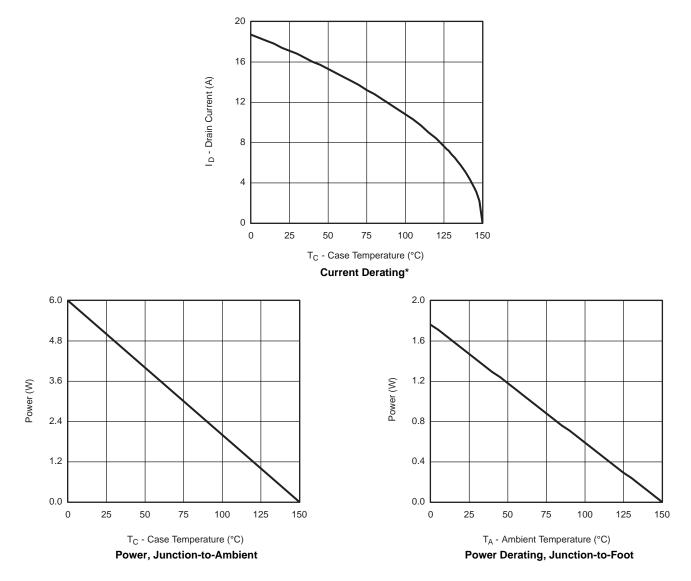


Safe Operating Area, Junction-to-Ambient

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

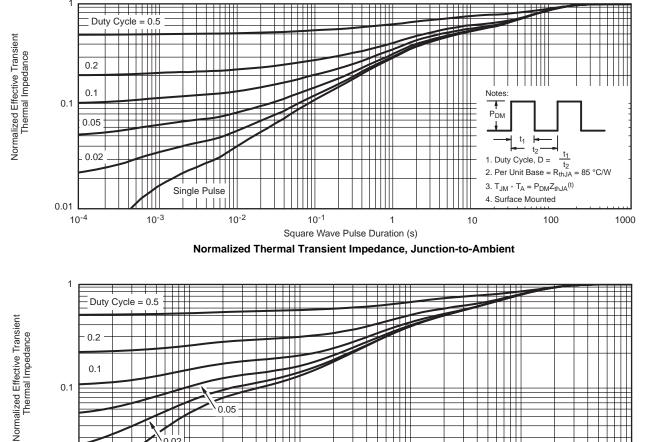


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

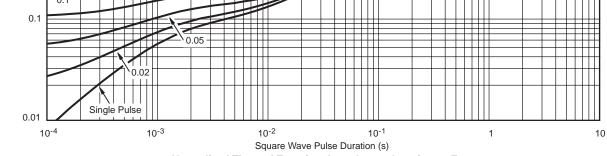


* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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TYPICAL CHARACTERISTICS 25 C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Foot

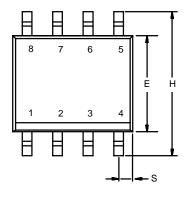
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SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

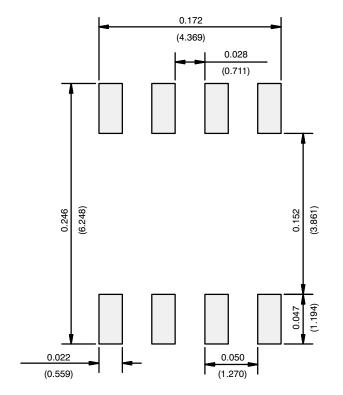




	MILLIM	IETERS	INCHES		
DIM	Min	Мах	Min	Max	
A	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27	BSC	0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498					



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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